

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. 455610-2590.3		SERIAL NO. 10/673,713	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Martin MILLER et al.			
FILING DATE September 29, 2003				GROUP 2186			

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/EC/		AB 5,726,607	03/10/98	Brede et al			
/EC/		AC 5,825,825	10/20/98	Altmann et al			
/EC/		AD 5,900,755	05/04/99	Toeppen et al			
/EC/		AE 6,215,363	04/10/01	Conta et al			
/EC/		AF 6,295,327	09/25/01	Takla			
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/EC/		AJ 6,188,737	02/13/01	Bruce et al			
/EC/		AK 5,914,592	06/22/99	Saito			
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/EC/		AN JP4105070	04/07/92	Japan			Abstract	
/EC/		AO JP5196641	08/06/93	Japan			Abstract	
/EC/		AP JP5264595	10/12/93	Japan			Abstract	
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/EC/		AV EP 0 631 143	12/28/94	Europe				
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/EC/	BA		HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
/EC/	BB		Infinium DCA, Agilent Technologies, March 7, 2002
/EC/	BC		Communication waveform measurement, Hewlett Packard, June 20, 1990

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ATTY. DOCKET NO.

455610-2590.3

SERIAL NO.

10/673,713

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/EC/	BW		University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003

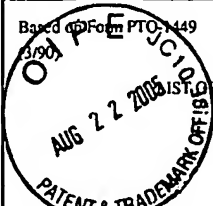
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	FILING DATE September 29, 2003	GROUP 2133

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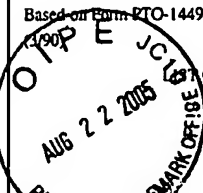
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